

TPC readout electronics discussion

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Readout situation

- We need electronics to readout. Based on the schedule outlined below, the electronics should be ready by the end of April next year
 - Roughly, one year from now
- We may want to establish a readout scheme that is also good for the final version if possible

Items	2015			2016												2017								
	10	11	12	1	2	3	4	5	6	7	8	9	10	11	12	1	2	3	4	5	6	7	8	9
Field Cage design					■	■	■	■																
Field Cage procurement							■		■	■	■	■	■											
Field Cage assembly							■							■	■	■	■	■	■					
GEM Blob production							■					■	■	■	■	■								
Chevron Pad ver1							■	■	■	■														
Chevron Pad ver2							■				■	■	■											
Chevron Pad ver3							■							■	■	■								
FEM Development							■	■	■	■	■	■	■	■	■	■	■	■	■					
Basic Performance test							■													■	■	■	■	
Beam Test							■																	■

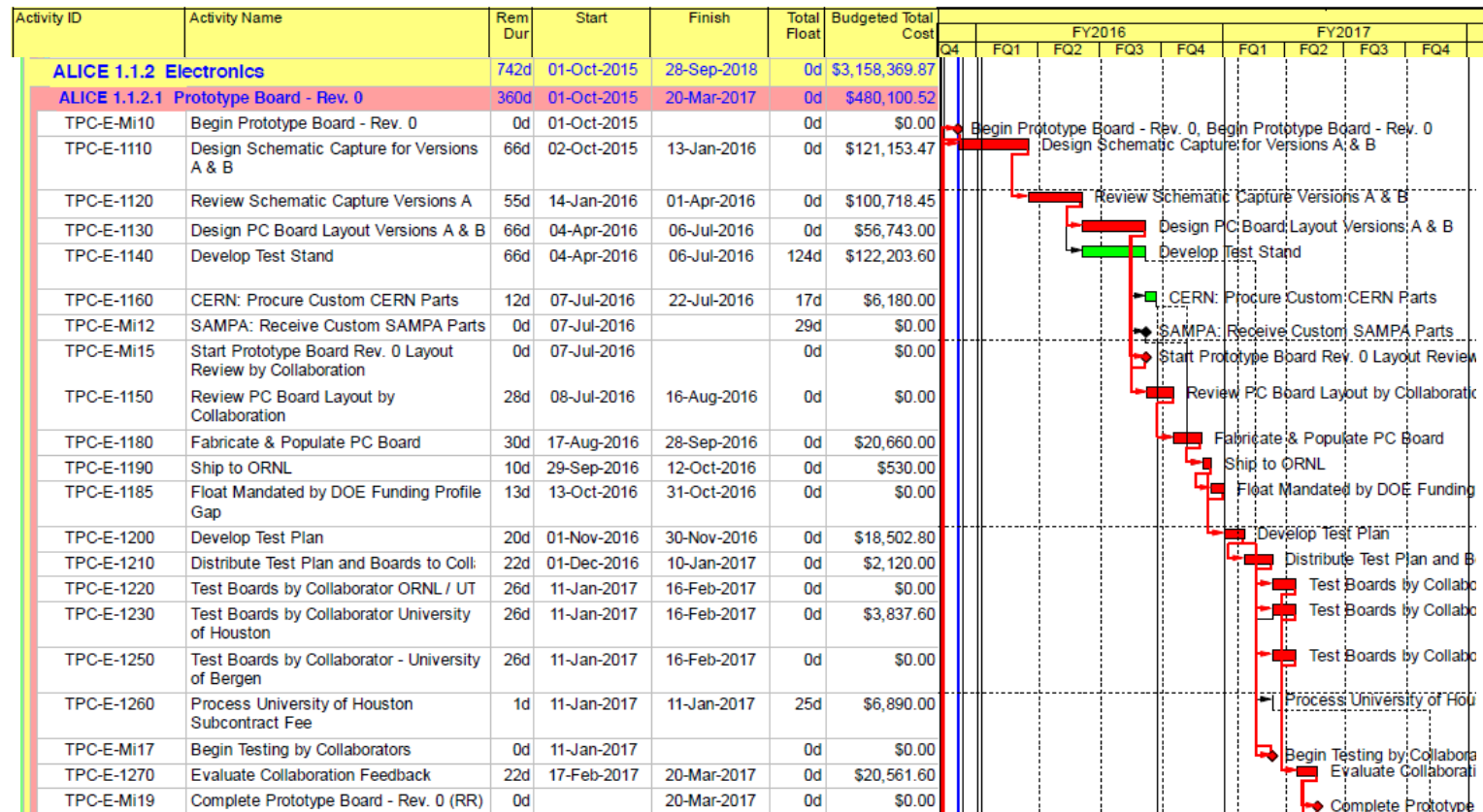
FNAL Beam test

Time scale of possible candidates

- We contacted ALICE TPC and STAR iTPC groups on their schedule
- ALICE TPC – uses SAMPA chips
 - Their schedule is to finish electronics by the installation time (Sep, 2018)
 - We wish to use a proto-type electronics?
 - Paul kindly said that he will ask Ken Read of ORNL to show up in a TPC meeting and tell us more detail.
- STAR iTPC – also uses SAMPA chips
 - They are expecting to receive proto-type of SAMPA chips this April. None of them has been provided by now
 - If they figured out that they can't receive in time, they will reuse current TPC electronics (PASA+ALTRO)
 - They will decided in April which way to go.
- sPHENIX TPC case – we have to use SAMPA if we go this direction
 - PASA+ALTRO accepts positive unipolar signal → for MWPC + pad readout
 - SAMPA accepts bipolar signal → only option for GEM + pad readout (negative)

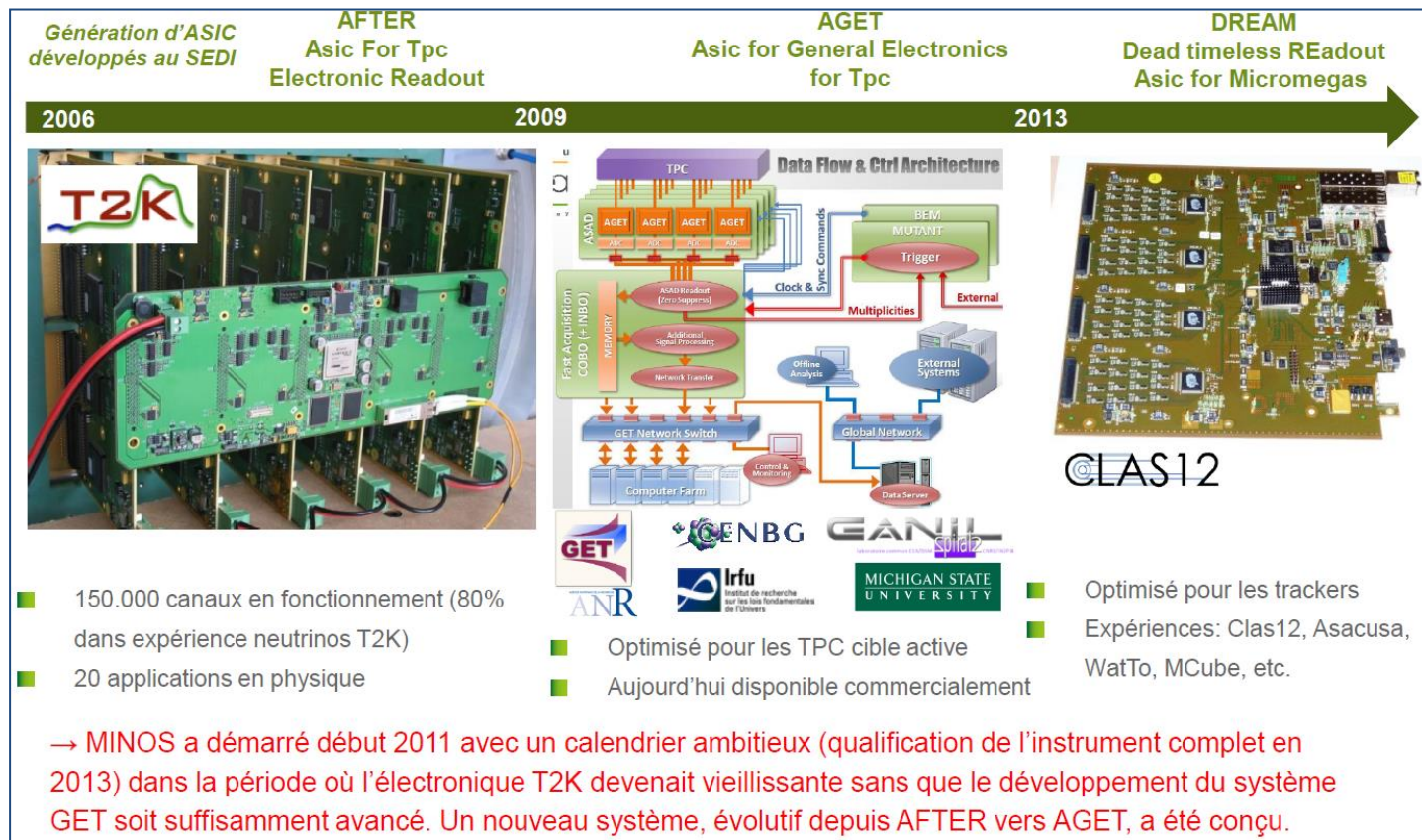
ALICE schedule from WBS last year

- The very first version of proto-type will be produced by the end of FY16
 - I thought they will produce ~10% of total. I should check
- One option is to join the test board effort?



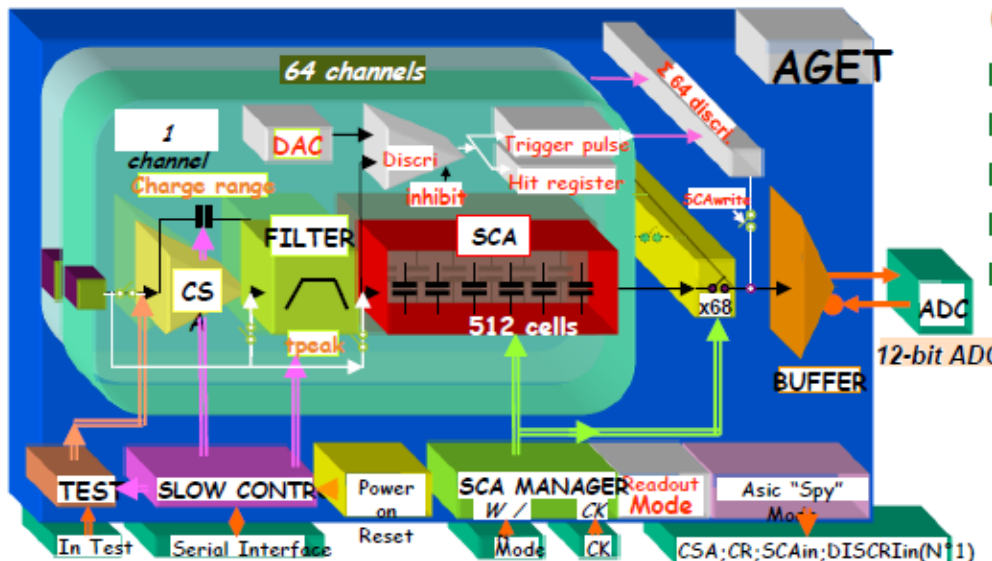
Let's DREAM? (but, for this R&D only?)

- Saclay Chips: AFTER → AGET → DREAM (Similar ingredient as SAMPA)
- With AGET chips, cost per channel is \$40 (Craig's quote) → \$8M for 200K channels -- three times more compared to ALICE TPC case (\$2.5M)



DREAM – successor of AGET

- Accept bipolar signal. One chip handles 64 channels
 - Four dynamic ranges: 50, 100, 200 and 600 fC (SAMPA: 100 fC)
 - 16 shaping time selection in 50 to 900nsec (SAMPA: 80 or 160nsec peaking)
 - Can handle detector capacitor up to 100pF
- 50MHz sampling with switched capacitor array (SCA, similar to AMU)
 - 512 samples can be stored
 - SCA values can be readout at 20MHz (SAMPA: 20MHz sample rate, no buffer)
 - External trigger and self-trigger can be chosen.
- It can be operated at 1T magnetic field, but not rad-hard



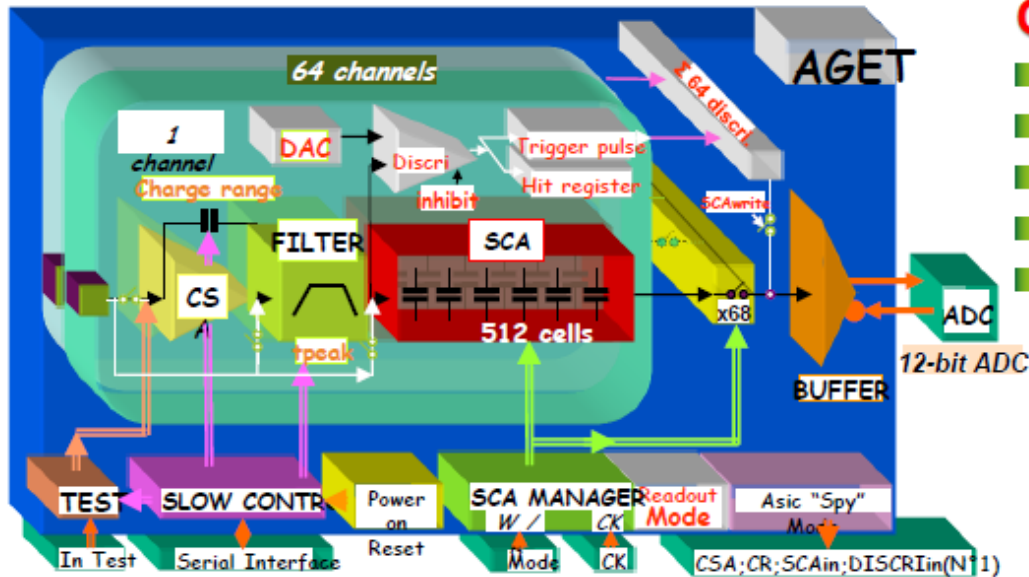
- Based on T2K TPC experience (125K channel), each channel would cost 3-4 euro excluding engineering costs, R&D and manpower → \$1M for 200K
- They can provide us either prototype electronics system or some left-over from the CLAS12 production

Discussion

- We can ask Ken Read to tell us the status of ALICE TPC electronics.
 - Using the proto-type electronics board will be sufficient for our R&D.
- In parallel, we can try getting some DREAM based electronics.
 - At least, for R&D and test beam, it seems useful.

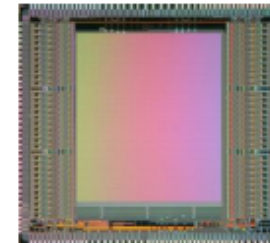
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DREAM – successor of AGET



Caractéristiques

- Technologie: AMS CMOS 0,35 μm
- Surface: 8,5 x 7,6 mm^2
- 700,000 transistors
- Boîtier: LQFP 160 (28 x 28 x 1,4 mm)
- Production (jusqu'à 2014): 3200 chips



- **64 voies analogiques.** Pour chacune: CSA, filtre, SCA (512 cells), *Discriminateur*
- **Auto trigger :** discriminateur par canal + seuil commun grossier + seuil fin par canal
- **Signal de Multiplicité :** somme analogique des discri. = nombre de canaux touchés
- **Registre Hit Channel.** Accessible en lecture et écriture avant numérisation du SCA
- **Lecture du SCA:** tout, canaux touchés, définis par l'utilisateur
- **4 gammes de mesure:** 120 fC; 240 fC; 1 pC; 10 pC (e.g. détecteurs Silicium)
- **Polarité du signal d'entrée positive ou negative, définie par registre de configuration**
- **Bypass possible du CSA:** permet d'utiliser un préampli/shaper externe

Source: P. Baron